

Issue Classification

Devin Hanan 11/10/05
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(Assistant Examiner) (Date)

Edward K. Look u/13/05
EDWARD K. LOOK
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Total Claims Allowed: 20	
O.G. Print Claim(s) 1,11	O.G. Print Fig. 4

☒ **Claims renumbered in the same order as presented by applicant**☐ CPA☐ T.D.

☐ R.1.47

EG